

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



Nobutoshi AOKI

Attorney Docket 40301/0578

Title:

SEMICONDUCTOR INTEGRATED CIRCUIT INCLUDING

INSULATED GATE FIELD EFFECT TRANSISTOR AND METHOD

OF MANUFACTURING THE SAME

Appl. No.:

09/440,928

Filing Date:

November 16, 1999

Examiner:

S. Rao

Art Unit:

2814

TRANSMITTAL

Commissioner for Patents Washington, D.C. 20231

Sir:

Transmitted herewith is a Preliminary Amendment in the above-captioned application. The fee has been calculated as shown below. (Small entity fees indicated in parentheses.)

CLAIMS AS AMENDED						
(1)	(2)	(3)	(4)	(5)	(6)	(7)
	Claims Remaining After Amendment		Highest Number Previously Paid For	Extra Claims	Rate	Fee
Total Claims	31	-	27	4	18.00	\$72.0
(Small Entity)					(9.00)	
Independent claims	10	-	9	1	84.00	\$84.0
(Small Entity)					(42.00)	
Multiple Dependent		-			280.00	
(Small Entity)					(140.00)	
Extension of Time	One Month		Two Months	Three Months	Four Months	
Fee	\$110		\$400	\$920	\$1,440	
(Small Entity)	(\$55)		(\$200)	(\$460)	(\$720)	
Total Fees						\$156.0

A check in the amount of the above Total Fees is attached. This amount is believed to be correct; however, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 19-0741.

Date: February 26, 2002

FOLEY & LARDNER 3000 K Street, N.W., Suite 500 Washington, D.C. 20007-5109 (202) 672-5300

Respectfully submitted,

Maron C. Chattegeo Aaron C. Chatterjee

Reg. No. 41,398

002.735640.1

THE UNITED STATES PATENT AND TRADEMARK OFFICE

Nobutoshi AOKI et al.

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AMENDMENT AND RESPONSE UNDER 37 C.F.R. § 1.111

Commissioner for Patents Washington, D.C. 20231

Sir:

In reply to the Office Action mailed November 26, 2001, please amend the aboveidentified application as follows:

IN THE CLAIMS:

Please amend the claims by replacing the indicated claims with the following clean versions. (See Attachment A for the marked up version of the amended claims.)

(Amended) A semiconductor device comprising: 1.

a pair of main electrodes used as source and drain electrodes;

an insulating gate film adjacent to the pair of main electrodes; and

a gate electrode comprising of a first region composed at least a first group IV element

and a second group IV element and formed in contact with the insulating gate film, and a

second region composed of the first group IV element and formed on the first region.

03/04/2002 SSITHIB1 00000033 09440928

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